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SCES563C-MARCH 2004-REVISED APRIL 2008

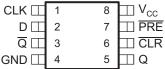
# SINGLE POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

#### **FEATURES**

- Qualified for Automotive Applications
- Supports 5-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 5.5 V
- Max t<sub>pd</sub> of 6.9 ns at 3.3 V
- Low Power Consumption, 10-μA Max I<sub>CC</sub>
- ±24-mA Output Drive at 3.3 V
- Typical  $V_{OLP}$  (Output Ground Bounce) <0.8 V at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot) >2 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II

- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)

# DCU PACKAGE (TOP VIEW)



### **DESCRIPTION/ORDERING INFORMATION**

This single positive-edge-triggered D-type flip-flop is designed for 1.65-V to 5.5-V  $V_{CC}$  operation.

A low level at the preset  $(\overline{PRE})$  or clear  $(\overline{CLR})$  input sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not related directly to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

This device is fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

#### ORDERING INFORMATION(1)

T <sub>A</sub>	PACKAG	SE <sup>(2)</sup>	ORDERABLE PART NUMBER	TOP-SIDE MARKING (3)
-40°C to 125°C	VSSOP - DCU	Reel of 3000	SN74LVC2G74QDCURQ1	C74_

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.
- (2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.
- (3) DCU: The actual top-side marking has one additional character that designates the wafer fab/assembly site.



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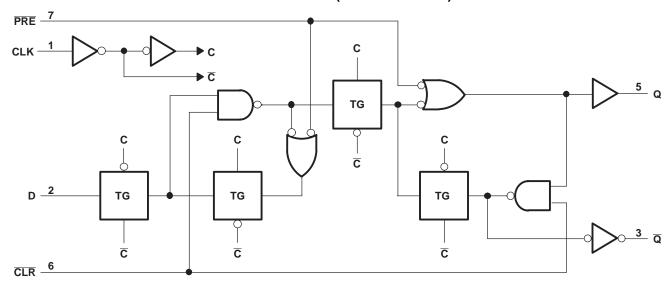


### **FUNCTION TABLE**

	INP	OUTPUTS			
PRE	CLR	CLK	D	Q	Ø
L	Н	Χ	Χ	Н	L
Н	L	Χ	Χ	L	Н
L	L	Χ	Χ	H <sup>(1)</sup>	H <sup>(1)</sup>
Н	Н	<b>↑</b>	Н	Н	L
Н	Н	<b>↑</b>	L	L	Н
Н	Н	L	Χ	$Q_0$	$\overline{Q}_0$

(1) This configuration is nonstable; that is, it does not persist when  $\overline{\text{PRE}}$  or  $\overline{\text{CLR}}$  returns to its inactive (high) level.

# **LOGIC DIAGRAM (POSITIVE LOGIC)**





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# Absolute Maximum Ratings(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage range		-0.5	6.5	
$V_{I}$	Input voltage range <sup>(2)</sup>			6.5	\ /
Vo	Voltage range applied to any output in the I	-0.5	6.5	V	
Vo	Voltage range applied to any output in the I	-0.5	V <sub>CC</sub> + 0.5		
I <sub>IK</sub>	Input clamp current	V <sub>1</sub> < 0		-50	
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	A
Io	Continuous output current			±50	mA
	Continuous current through V <sub>CC</sub> or GND		±100		
$\theta_{JA}$	Package thermal impedance (4)		227	°C/W	
T <sub>stg</sub>	Storage temperature range	-65	150	°C	

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

<sup>(2)</sup> The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(3)</sup> The value of V<sub>CC</sub> is provided in the recommended operating conditions table.

<sup>(4)</sup> The package thermal impedance is calculated in accordance with JESD 51-7.



# Recommended Operating Conditions<sup>(1)</sup>

			MIN	MAX	UNIT
	Complexed to me	Operating	1.65	5.5	V
V <sub>CC</sub>	Supply voltage	Data retention only	1.5		V
		V <sub>CC</sub> = 1.65 V to 1.95 V	$0.65 \times V_{CC}$		
.,	High lavel input valtage	V <sub>CC</sub> = 2.3 V to 2.7 V	1.7		V
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V	2		V
		V <sub>CC</sub> = 4.5 V to 5.5 V	$0.7 \times V_{CC}$		
		V <sub>CC</sub> = 1.65 V to 1.95 V		$0.35 \times V_{CC}$	
\ /	Law lawal innut waltana	V <sub>CC</sub> = 2.3 V to 2.7 V		0.7	V
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V		0.8	V
		V <sub>CC</sub> = 4.5 V to 5.5 V		$0.3 \times V_{CC}$	
V <sub>I</sub>	Input voltage		0	5.5	V
Vo	Output voltage		0	V <sub>CC</sub>	٧
		V <sub>CC</sub> = 1.65 V		-4	
		V <sub>CC</sub> = 2.3 V		-8	
I <sub>OH</sub>	High-level output current	evel output current		-16	mA
		$V_{CC} = 3 V$		-24	
		V <sub>CC</sub> = 4.5 V		-24	
		V <sub>CC</sub> = 1.65 V		4	
		V <sub>CC</sub> = 2.3 V		8	
$I_{OL}$	Low-level output current	V 0V		16	mA
		$V_{CC} = 3 V$		24	
		V <sub>CC</sub> = 4.5 V		24	
		$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}, 2.5 \text{ V} \pm 0.2 \text{ V}$		20	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		10	ns/V
		$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$		5	
T <sub>A</sub>	Operating free-air temperature	,	-40	125	°C

<sup>(1)</sup> All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

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### **Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

F	PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN TYP <sup>(1)</sup> MAX	UNIT
		$I_{OH} = -100 \mu A$	1.65 V to 5.5 V	V <sub>CC</sub> - 0.1	
		$I_{OH} = -4 \text{ mA}$	1.65 V	1.2	·
\/	$V_{OH}$	$I_{OH} = -8 \text{ mA}$	2.3 V	1.85	V
VOH		$I_{OH} = -16 \text{ mA}$	3 V	2.4	V
		L = 24 mΛ	3 V	2.3	
		$I_{OH} = -24 \text{ mA}$	4.5 V	3.8	
		I <sub>OL</sub> = 100 μA	1.65 V to 5.5 V	0.1	
		I <sub>OL</sub> = 4 mA	1.65 V	0.45	·
.,		I <sub>OL</sub> = 8 mA	2.3 V	0.3	V
V <sub>OL</sub>		I <sub>OL</sub> = 16 mA	3 V	0.4	V
		1 24 mA	3 V	0.55	·
		I <sub>OL</sub> = 24 mA	4.5 V	0.55	·
I	Data or control inputs	V <sub>I</sub> = 5.5 V or GND	0 to 5.5 V	±5	μΑ
I <sub>off</sub>		$V_I$ or $V_O = 5.5 \text{ V}$	0	±10	μΑ
$I_{CC}$		$V_I = 5.5 \text{ V or GND}, \qquad I_O = 0$	1.65 V to 5.5 V	10	μΑ
$\Delta I_{CC}$	;	One input at $V_{CC} - 0.6 \text{ V}$ , Other inputs at $V_{CC}$ or GND	3 V to 5.5 V	500	μΑ
C <sub>i</sub>		V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V	5	pF

<sup>(1)</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C.

# **Timing Requirements**

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			V <sub>CC</sub> = ± 0.1		V <sub>CC</sub> = ± 0.	2.5 V .2 V	V <sub>CC</sub> = 3 ± 0.3		V <sub>CC</sub> = ± 0.5		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
f <sub>clock</sub>				80		120		120		140	MHz	
	4 Dulas duration	CLK	6.2		3.5		3.5		3.3			
t <sub>w</sub>	Pulse duration	PRE or CLR low	6.2		3.5		3.5		3.3		ns	
	Catum times hafana CLIVA	Data	3.5		2.3		1.9		1.7			
t <sub>su</sub> Setup time befo	Setup time before CLK↑	PRE or CLR inactive	2.5		2		1.8		1.6		ns	
t <sub>h</sub>	Hold time, data after CLK↑		0		0.3		0.5		0.8		ns	

# **Switching Characteristics**

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 5 V ± 0.5 V		UNIT
	(INFOT)	(001F01)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			80		120		120		140		MHz
	CLK	Q	4.8	14.4	2.2	8.1	2.2	6.9	1.4	5.1	
t <sub>pd</sub>	CLK	Q	6	16	3	9.7	2.6	7.2	1.6	5.4	ns
	PRE or CLR	Q or $\overline{Q}$	4.4	14.9	2.3	9.5	1.7	7.9	1.6	6.1	

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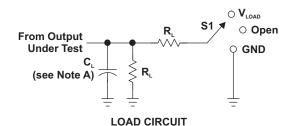
# **Operating Characteristics**

 $T_A = 25^{\circ}C$ 

PARAMETER		TEST CONDITIONS	V <sub>CC</sub> = 1.8 V V <sub>CC</sub> = 2.5		V <sub>CC</sub> = 3.3 V	V <sub>CC</sub> = 5 V	UNIT
		TEST CONDITIONS	TYP	TYP TYP		TYP	ГҮР
$C_{pd}$	Power dissipation capacitance	f = 10 MHz	35	35	37	40	pF

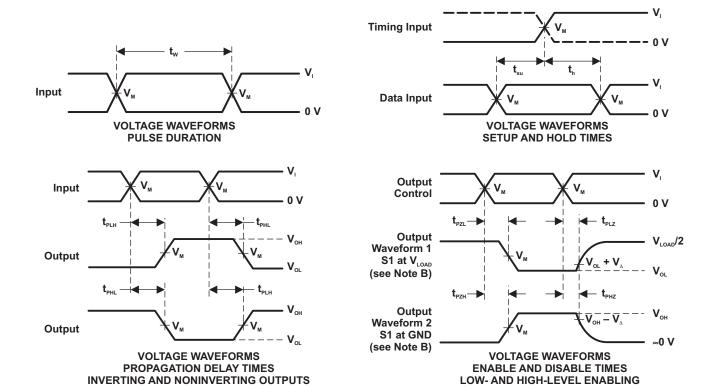


#### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	V <sub>LOAD</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

.,	INF	INPUTS		V		-	.,,
V <sub>cc</sub>	V,	t,/t,	V <sub>M</sub>	<b>V</b> <sub>LOAD</sub>	C <sup>r</sup>	$R_{\scriptscriptstyle L}$	V <sub>A</sub>
1.8 V ± 0.15 V	V <sub>cc</sub>	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V ± 0.2 V	$V_{cc}$	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	<b>500</b> Ω	0.15 V
3.3 V ± 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	50 pF	<b>500</b> Ω	0.3 V
5 V ± 0.5 V	$V_{cc}$	≤2.5 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	50 pF	<b>500</b> Ω	0.3 V



NOTES: A. C, includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_{o}$  = 50  $\Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{PLZ}$  and  $\dot{t}_{PHZ}$  are the same as  $t_{dis}$ .
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{\mbox{\tiny PLH}}$  and  $t_{\mbox{\tiny PHL}}$  are the same as  $t_{\mbox{\tiny pd}}.$
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms



## PACKAGE OPTION ADDENDUM

17-Aug-2015

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
CLVC2G74QDCURG4Q1	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74R	Samples
SN74LVC2G74QDCURQ1	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74R	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

17-Aug-2015

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74LVC2G74-Q1:

Catalog: SN74LVC2G74

Enhanced Product: SN74LVC2G74-EP

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications

# PACKAGE MATERIALS INFORMATION

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# TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LVC2G74QDCURQ1	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3

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#### \*All dimensions are nominal

Device Package Type		Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
SN74LVC2G74QDCURQ1	VSSOP	DCU	8	3000	202.0	201.0	28.0	

# DCU (R-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



NOTES:

- A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
  - D. Falls within JEDEC MO-187 variation CA.



DCU (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE (DIE DOWN)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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